

MOS FIELD EFFECT TRANSISTOR

2SK2070

N-CHANNEL MOS FET FOR HIGH-SPEED SWITCHING

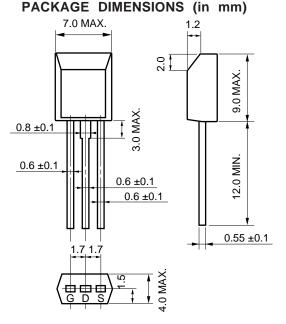
The 2SK2070 is a N-channel MOS FET of a vertical type and is a switching element that can be directly driven by the output of an IC operating at 5 V.

This product has a low ON resistance and superb switching characteristics and is ideal for driving the actuators, such as motors and DC/DC converters.

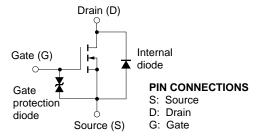
FEATURES

- New package intermediate between small-signal and power models
- Can be directly driven by output of 5-V IC
- · Low ON resistance

 $R_{DS(on)} = 0.45~\Omega~MAX.~@V_{GS} = 4~V,~I_{D} = 1.0~A$ $R_{DS(on)} = 0.35~\Omega~MAX.~@V_{GS} = 10~V,~I_{D} = 1.0~A$



EQUIVALENT CIRCUIT



ABSOLUTE MAXIMUM RATINGS (TA = 25 °C)

| PARAMETER | SYMBOL | TEST CONDITIONS | RATING | UNIT |
|-------------------------|------------------------|---------------------|-------------|------|
| Drain to Source Voltage | Voss | Vgs = 0 | 100 | V |
| Gate to Source Voltage | Vgss | V _{DS} = 0 | ±20 | V |
| Drain Current (DC) | I _{D(DC)} | | ±1.5 | Α |
| Drain Current (Pulse) | I _D (pulse) | PW ≤ 10 ms, | ±3.0 | А |
| | | Duty cycle ≤ 50 % | | |
| Total Power Dissipation | Рт | | 1.0 | W |
| Channel Temperature | Tch | | 150 | °C |
| Storage Temperature | T _{stg} | | -55 to +150 | °C |



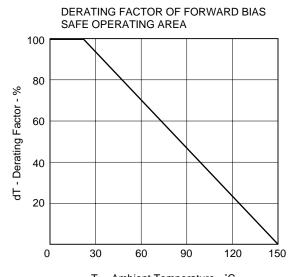
ELECTRICAL CHARACTERISTICS (Ta = 25 °C)

| PARAMETER | SYMBOL | TEST CONDITIONS | MIN. | TYP. | MAX. | UNIT |
|-------------------------------------|----------|--|------|------|------|------|
| Drain Cut-Off Current | IDSS | V _{DS} = 100 V, V _{GS} = 0 | | | 1.0 | μΑ |
| Gate Leakage Current | Igss | $V_{GS} = \pm 20 \text{ V}, V_{DS} = 0$ | | | ±10 | μΑ |
| Gate Cut-Off Voltage | Vgs(off) | V _{DS} = 10 V, I _D = 1 mA | 0.8 | 1.2 | 2.0 | V |
| Forward Transfer Admittance | yfs | V _{DS} = 10 V, I _D = 1.0 A | 2.0 | | | S |
| Drain to Source On-State Resistance | RDS(on)1 | Vgs = 4 V, ID = 1.0 A | | 0.28 | 0.45 | Ω |
| Drain to Source On-State Resistance | RDS(on)2 | Vgs = 10 V, ID = 1.0 A | | 0.24 | 0.35 | Ω |
| Input Capacitance | Ciss | V _{DS} = 10 V, V _{GS} = 0, | | 530 | | pF |
| Output Capacitance | Coss | f = 1.0 MHz | | 150 | | pF |
| Reverse Transfer Capacitance | Crss | | | 30 | | pF |
| Turn-On Delay Time | td(on) | V _{DD} = 10 V, I _D = 1.0 A | | 5 | | ns |
| Rise Time | tr | $V_{GS(on)}$ = 10 V, R_G = 10 Ω | | 50 | | ns |
| Turn-Off Delay Time | td(off) | R _L = 10 Ω | | 90 | | ns |
| Fall Time | tf | | | 15 | | ns |

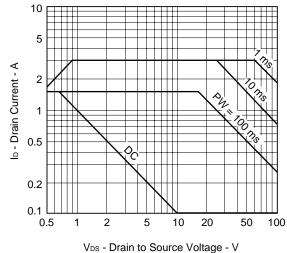
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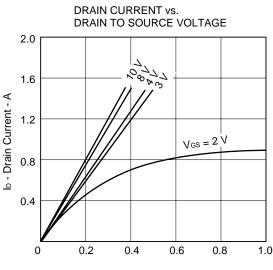
TYPICAL CHARACTERISTICS (TA = 25 °C)



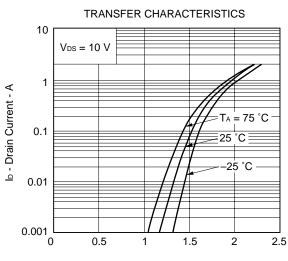
TA - Ambient Temperature - °C



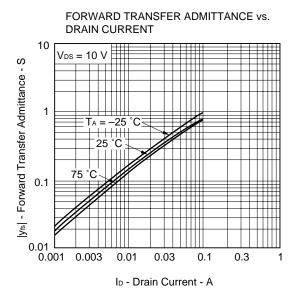
FORWARD BIAS SAFE OPERATING AREA

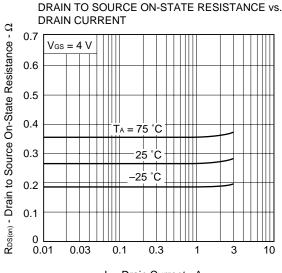


V_{DS} - Drain to Source Voltage - V



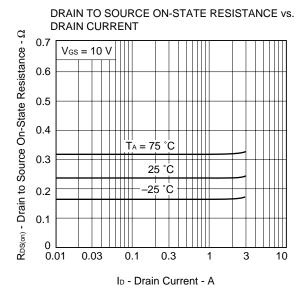
V_{GS} - Gate to Source Voltage - V

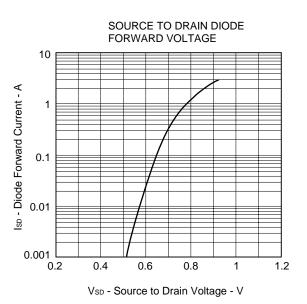


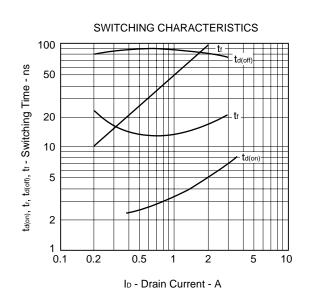


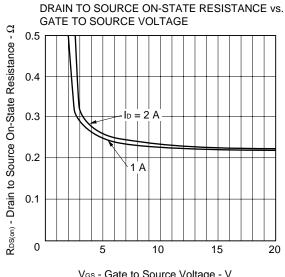
ID - Drain Current - A



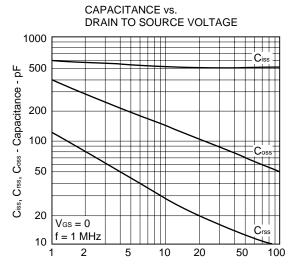








V_{GS} - Gate to Source Voltage - V



V_{DS} - Drain to Source Voltage - V



REFERENCE

| Document Name | Document No. | | |
|---|--------------|--|--|
| NEC semiconductor device reliability/quality control system | TEI-1202 | | |
| Quality grade on NEC semiconductor devices | IEI-1209 | | |
| Semiconductor device mounting technology manual | C10535E | | |
| Guide to quality assurance for semiconductor devices | MEI-1202 | | |
| Semiconductor selection guide | X10679E | | |

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Anti-radioactive design is not implemented in this product.